

# LMV331 Single, LMV393 Dual, LMV339 Quad General-purpose Low-voltage **Comparators**

#### 1 Features

- 2.7-V and 5-V Performance
- Low Supply Current
  - LMV331 130 µA Typ
  - LMV393 210 µA Typ
  - LMV339 410 µA Typ
- Input Common-Mode Voltage Range Includes Ground
- Low Output Saturation Voltage 200 mV Typical
- Open-Collector Output for Maximum Flexibility

## 2 Applications

- **Hysteresis Comparators**
- Oscillators
- **Window Comparators**
- Industrial Equipment
- Test and Measurement

## 3 Description

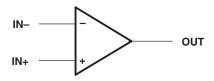
The LMV393 and LMV339 devices are low-voltage (2.7 V to 5.5 V) versions of the dual and quad comparators, LM393 and LM339, which operate from 5 V to 30 V. The LMV331 is the single-comparator version.

The LMV331, LMV339, and LMV393 are the most cost-effective solutions for applications where lowvoltage operation, low power, and space saving are the primary specifications in circuit design for portable consumer products. These devices specifications that meet or exceed the familiar LM339 and LM393 devices at a fraction of the supply current.

#### **Device Information**

PART NUMBER	PACKAGE (PIN)(1)	BODY SIZE (NOM)
LMV339	SOIC (14)	8.65 mm x 3.90 mm
LMV393	SOIC (8)	4.90 mm x 3.90 mm
LMV331	SC70 (5)	2.00 mm x 1.25 mm

For all available packages, see the orderable addendum at the end of the datasheet.



**Simplified Schematic** 

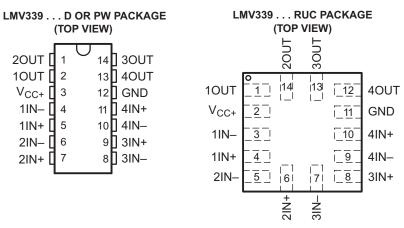


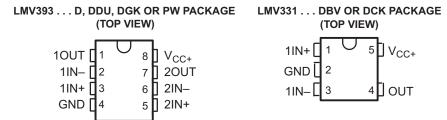
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## 5 Pin Configuration and Functions





**Table 5-1. Pin Functions** 

		PIN						
	LMV331	LMV393	LM	V339	TYPE	DESCRIPTION		
NAME	DBV or DCK	D, DDU, DGK or PW	D or PW	RUC		Section Field		
1IN-, 2IN-, 3IN-, 4IN-	3	2, 6	4, 6, 8, 10	3, 5, 7, 9	I	Comparator(s) negative input pin(s)		
1IN+ , 2IN+, 3IN+, 4IN+	1	3, 5	5, 7, 9, 11	4, 6, 8, 10	I	Comparator(s) positive input pin(s)		
GND	2	4	12	11	I	Ground		
10UT, 20UT, 30UT, 40UT	4	1, 7	2, 1, 14, 13	1, 14, 13, 12	0	Comparator(s) output pin(s)		
V <sub>CC+</sub>	5	8	3	2	I	Supply Pin		



## **6 Specifications**

## **6.1 Absolute Maximum Ratings**

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage <sup>(2)</sup>			5.5	V
$V_{ID}$	Differential input voltage <sup>(3)</sup>			±5.5	V
VI	Input voltage range (either input)			V <sub>CC+</sub>	V
	Duration of output short circuit (one amplifier) to ground <sup>(4)</sup>	At or below $T_A = 25$ °C, $V_{CC} \le 5.5 \text{ V}$	U	Inlimited	
TJ	Operating virtual junction temperature			150	°C
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Section 6.3 is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## 6.2 ESD Ratings

			VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins <sup>(1)</sup>	±2000	
V <sub>(ESD)</sub>	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins <sup>(2)</sup>	±1000	V

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

## **6.3 Recommended Operating Conditions**

		MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage (single-supply operation)	2.7	5.5	V
V <sub>OUT</sub>	Output voltage	,	V <sub>CC+</sub> + 0.3	V
T <sub>A</sub>	Operating free-air temperature	-40	125	°C

## **6.4 Thermal Information**

			LMV339			LM\	/393		LM	<b>/</b> 331	
TH	ERMAL METRIC(1)	D	PW	RUC	D	DDU	DGK	PW	DBV	DCK	UNIT
			14 PINS			8 P	INS		5 P	INS	
R <sub>θJA</sub>	Junction-to-ambient thermal resistance	86	113	216	97	210	172	149	206	252	
R <sub>θJC(top)</sub>	Junction-to-case (top) thermal resistance	_	_	51.3	_	_	_	_	_	_	
R <sub>θJB</sub>	Junction-to-board thermal resistance	_	_	59.0	_	_	_	_	_	_	°C/W
ΤιΨ	Junction-to-top characterization parameter	_	_	1.2	_	_	_	_	_	_	
ΨЈВ	Junction-to-board characterization parameter	_	_	59.0	_	_	_	_	_	_	

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

<sup>(2)</sup> All voltage values (except differential voltages and V<sub>CC</sub> specified for the measurement of I<sub>OS</sub>) are with respect to the network GND.

<sup>(3)</sup> Differential voltages are at IN+ with respect to IN-.

<sup>(4)</sup> Short circuits from outputs to  $V_{CC}$  can cause excessive heating and eventual destruction.

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



# 6.5 Electrical Characteristics, $V_{CC+} = 2.7 \text{ V}$

 $V_{CC+}$  = 2.7 V, GND = 0 V, at specified free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN TYP	MAX	UNIT	
V <sub>IO</sub>	Input offset voltage		25°C	1.7	7	mV	
$\alpha_{VIO}$	Average temperature coefficient of input offset voltage		–40°C to 125°C	5		μV/°C	
			25°C	15	250		
I <sub>IB</sub>	Input bias current		–40°C to 125°C		400	nA	
			25°C	5	50		
I <sub>IO</sub>	Input offset current		-40°C to 125°C		150	150 nA	
Io	Output current (sinking)	V <sub>O</sub> ≤ 1.5 V	25°C	5 23		mA	
			25°C	0.003			
	Output Leakage Current		-40°C to 125°C		1	μΑ	
V <sub>ICR</sub>	Common-mode input voltage range		25°C	-0.1 to 2		V	
V <sub>SAT</sub>	Saturation voltage	I <sub>O</sub> ≤ 1.5 mA	25°C	200		mV	
		LMV331	25°C	40	100		
$I_{CC}$	Supply current	LMV393 (both comparators)	25°C	70	140	μΑ	
		LMV339 (all four comparators)	25°C	140	200		



## 6.6 Electrical Characteristics, $V_{CC+} = 5 \text{ V}$

 $V_{CC+}$  = 5 V, GND = 0 V, at specified free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
			25°C		1.7	7	
$V_{IO}$	Input offset voltage		-40°C to 125°C			9	mV
$\alpha_{VIO}$	Average temperature coefficient of input offset voltage		25°C		5		μV/°C
			25°C		25	250	
I <sub>IB</sub>	Input bias current		–40°C to 125°C			400	nA
			25°C		2	50	
I <sub>IO</sub>	Input offset current		–40°C to 125°C			150	nA
Io	Output current (sinking)	V <sub>O</sub> ≤ 1.5 V	25°C	10	84		mA
			25°C		0.003		
	Output Leakage Current		–40°C to 125°C			1	μΑ
V <sub>ICR</sub>	Common-mode input voltage range		25°C	-(	0.1 to 4.2		V
A <sub>VD</sub>	Large-signal differential voltage gain		25°C	20	50		V/mV
			25°C		200	400	
$V_{SAT}$	Saturation voltage	I <sub>O</sub> ≤ 4 mA	-40°C to 125°C			700	mV
			25°C		60	120	
		LMV331	-40°C to 125°C			150	
			25°C		100	200	
I <sub>CC</sub>	Supply current	LMV393 (both comparators)	–40°C to 125°C			250	μΑ
			25°C		170	300	
		LMV339 (all four comparators)	-40°C to 125°C			350	

# 6.7 Switching Characteristics, $V_{CC+} = 2.7 \text{ V}$

 $T_A = 25$ °C,  $V_{CC+} = 2.7$  V,  $R_L = 5.1$  k $\Omega$ , GND = 0 V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	TYP	UNIT
	Propagation delay high to low level output switching	Input overdrive = 10 mV	1000	no
<sup>L</sup> PHL		Input overdrive = 100 mV	350	ns
	Propagation delay low to high level output	Input overdrive = 10 mV	500	no
t <sub>PLH</sub>	switching	Input overdrive = 100 mV	400	ns



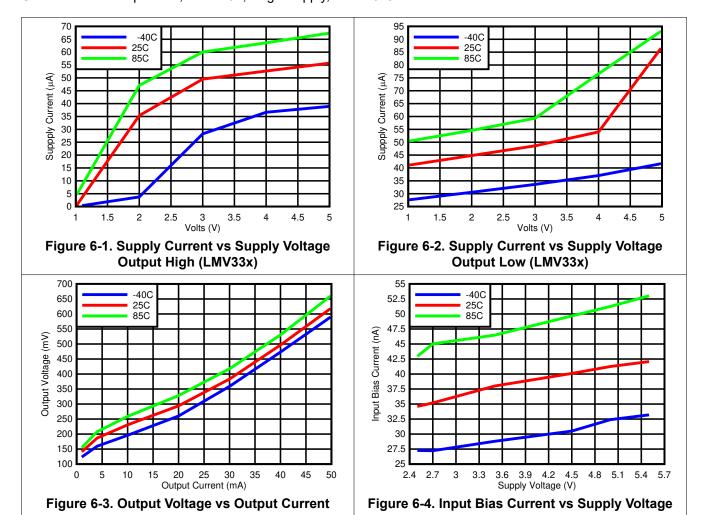
## 6.8 Switching Characteristics, V<sub>CC+</sub> = 5 V

 $T_A = 25$ °C,  $V_{CC+} = 5$  V,  $R_L = 5.1$  k $\Omega$ , GND = 0 V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	TYP	UNIT
	Propagation delay high to low level output switching	Input overdrive = 10 mV	600	ne
<sup>T</sup> PHL		Input overdrive = 100 mV	200	ns
Propagation delay low to high level output		Input overdrive = 10 mV	450	no
t <sub>PLH</sub>	switching	Input overdrive = 100 mV	300	ns

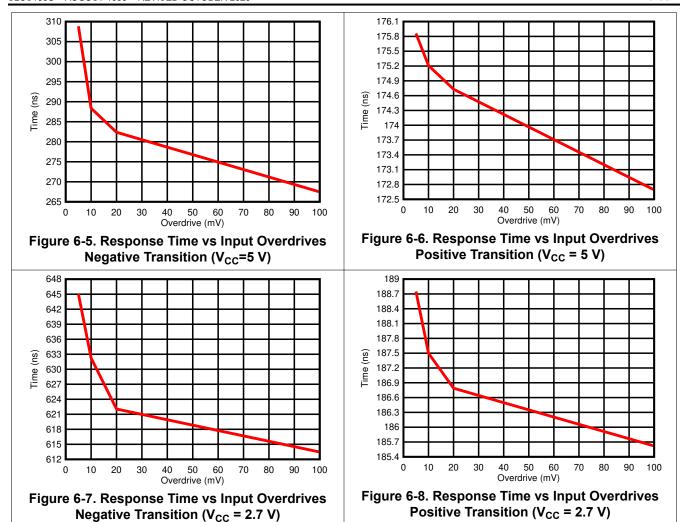
## 6.9 Typical Characteristics

Unless otherwise specified, VS = +5V, single supply, TA = 25°C



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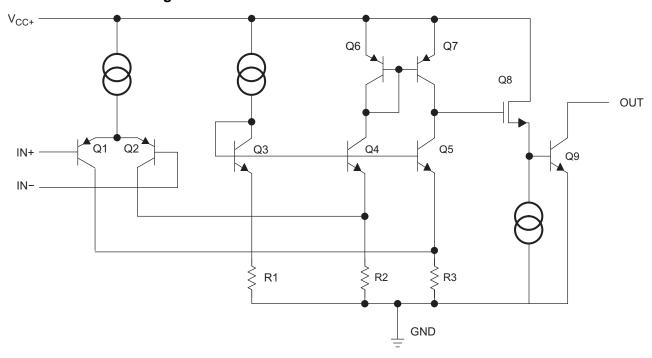
## 7 Detailed Description

#### 7.1 Overview

The LMV331, LMV393 and LMV339 family of comparators have the ability to operate up to 5 V on the supply pin. This standard device has proven ubiquity and versatility across a wide range of applications. This is due to it's low lq and fast response.

The open-drain output allows the user to configure the output's logic low voltage  $(V_{OL})$  and can be utilized to enable the comparator to be used in AND functionality.

#### 7.2 Functional Block Diagram



## 7.3 Feature Description

The LMV393 and LMV339 consists of a PNP input, whose Vbe creates a limit on the input common mode voltage capability, allowing LMV33x to accurately function from ground to  $V_{CC}$ -Vbe(~700mV) differential input. This enables much head room for modern day supplies of 3.3 V and 5.0 V.

The output consists of an open drain NPN (pull-down or low side) transistor. The output NPN will sink current when the positive input voltage is higher than the negative input voltage and the offset voltage. The  $V_{OL}$  is resistive and will scale with the output current. Please see Figure 6-3 for  $V_{OL}$  values with respect to the output current.

#### 7.4 Device Functional Modes

## 7.4.1 Voltage Comparison

The LMV33x operates solely as a voltage comparator, comparing the differential voltage between the positive and negative pins and outputs a logic low or high impedance (logic high with pull-up) based on the input differential polarity.

## 8 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

### 8.1 Application Information

LMV331, LMV393, and LMV339 will typically be used to compare a single signal to a reference or two signals against each other. Many users take advantage of the open drain output to drive the comparison logic output to a logic voltage level to an MCU or logic device. The wide supply range and high voltage capability makes LMV331, LMV393, and LMV33 optimal for level shifting to a higher or lower voltage.

## 8.2 Typical Application

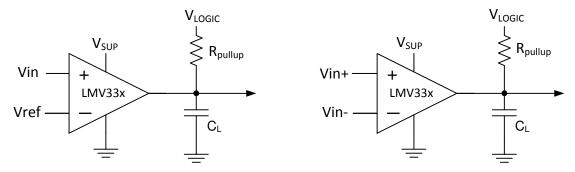


Figure 8-1. Typical Application Schematic

#### 8.2.1 Design Requirements

For this design example, use the parameters listed in Table 8-1 as the input parameters.

**DESIGN PARAMETER EXAMPLE VALUE** Input Voltage Range 0 V to 4.2 V Supply Voltage 2.7 V to 5V Logic Supply Voltage (RPULLUP Voltage) 1 V to 5 V Output Current (V<sub>LOGIC</sub>/R<sub>PULLUP</sub>)  $1 \mu A$  to 20 mAInput Overdrive Voltage 100 mV 2.5 V Reference Voltage Load Capacitance (C<sub>I</sub>) 15 pF

Table 8-1. Design Parameters

### 8.2.2 Detailed Design Procedure

When using LMV331, LMV393, and LMV33 in a general comparator application, determine the following:

- Input Voltage Range
- Minimum Overdrive Voltage
- Output and Drive Current
- Response Time

#### 8.2.2.1 Input Voltage Range

When choosing the input voltage range, the input common mode voltage range ( $V_{ICR}$ ) must be taken in to account. If operating temperature is above or below 25°C the  $V_{ICR}$  can range from 0 V to  $V_{CC}$ – 0.7 V. This limits the input voltage range to as high as  $V_{CC}$ – 0.7 V and as low as 0 V. Operation outside of this range can yield incorrect comparisons.

Below is a possible list of input voltage situation and their outcomes:

- 1. When both IN- and IN+ are both within the common mode range:
  - a. If IN- is higher than IN+ and the offset voltage, the output is low and the output transistor is sinking current
  - b. If IN- is lower than IN+ and the offset voltage, the output is high impedance and the output transistor is not conducting
- 2. When IN- is higher than common mode and IN+ is within common mode, the output is low and the output transistor is sinking current
- 3. When IN+ is higher than common mode and IN- is within common mode, the output is high impedance and the output transistor is not conducting
- 4. When IN- and IN+ are both higher than common mode, the output is low and the output transistor is sinking current

#### 8.2.2.2 Minimum Overdrive Voltage

Overdrive Voltage is the differential voltage produced between the positive and negative inputs of the comparator over the offset voltage ( $V_{IO}$ ). In order to make an accurate comparison; the Overdrive Voltage ( $V_{OD}$ ) should be higher than the input offset voltage ( $V_{IO}$ ). Overdrive voltage can also determine the response time of the comparator, with the response time decreasing with increasing overdrive. Figure 8-2 show positive and negative response times with respect to overdrive voltage.

#### 8.2.2.3 Output and Drive Current

Output current is determined by the pull-up resistance (Rpullup) and Vlogic voltage, refer to Figure 8-1. The output current will produce a output low voltage ( $V_{OL}$ ) from the comparator. In which  $V_{OL}$  is proportional to the output current. Use Figure 6-3 to determine  $V_{OL}$  based on the output current.

The output current can also effect the transient response. More will be explained in the next section.

#### 8.2.2.4 Response Time

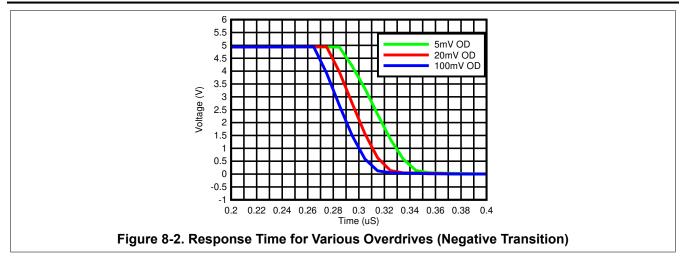
The transient response can be determined by the load capacitance ( $C_L$ ), load/pull-up resistance ( $R_{PULLUP}$ ) and equivalent collector-emitter resistance ( $R_{CE}$ ).

- The positive response time (τ<sub>p</sub>) is approximately τ<sub>P</sub> ~ R<sub>PULLUP</sub> × C<sub>L</sub>
- The negative response time (τ<sub>N</sub>) is approximately τ<sub>N</sub> ~ R<sub>CE</sub> × C<sub>L</sub>
  - R<sub>CE</sub> can be determine by taking the slope of Figure 6-3 in it's linear region at the desired temperature, or by dividing the V<sub>OL</sub> by I<sub>out</sub>

#### 8.2.3 Application Curves

The following curves were generated with 5 V on  $V_{CC}$  and  $V_{Logic}$ ,  $R_{PULLUP}$  = 5.1 k $\Omega$ , and 50 pF scope probe.





## 9 Power Supply Recommendations

For fast response and comparison applications with noisy or AC inputs, it is recommended to use a bypass capacitor on the supply pin to reject any variation on the supply voltage. This variation cause temporary fluctuations in the comparator's input common mode range and create an inaccurate comparison.

## 10 Layout

### 10.1 Layout Guidelines

For accurate comparator applications without hysteresis it is important maintain a stable power supply with minimized noise and glitches, which can affect the high level input common mode voltage range. In order to achieve this, it is best to add a bypass capacitor between the supply voltage and ground. This should be implemented on the positive power supply and negative supply (if available). If a negative supply is not being used, do not put a capacitor between the IC's GND pin and system ground.

## 10.2 Layout Example

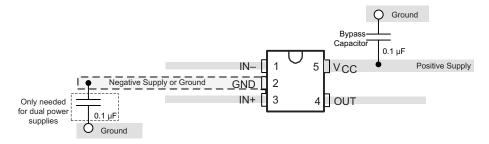


Figure 10-1. LMV331 Layout Example



## 11 Device and Documentation Support

#### 11.1 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 11-1. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
LMV331	Click here	Click here	Click here	Click here	Click here
LMV393	Click here	Click here	Click here	Click here	Click here
LMV339	Click here	Click here	Click here	Click here	Click here

#### 11.2 Trademarks

All other trademarks are the property of their respective owners.

## 11.3 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 11.4 Glossary

**TI Glossary** 

This glossary lists and explains terms, acronyms, and definitions.

## 12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.





11-Apr-2023 www.ti.com

## **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
LMV331IDBVR	ACTIVE	SOT-23	DBV	5	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	(R1IF, R1IK)	Samples
LMV331IDBVRE4	ACTIVE	SOT-23	DBV	5	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	(R1IF, R1IK)	Samples
LMV331IDBVRG4	ACTIVE	SOT-23	DBV	5	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	(R1IF, R1IK)	Samples
LMV331IDBVT	ACTIVE	SOT-23	DBV	5	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	(R1IF, R1IK)	Samples
LMV331IDBVTG4	ACTIVE	SOT-23	DBV	5	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	(R1IF, R1IK)	Samples
LMV331IDCKR	ACTIVE	SC70	DCK	5	3000	RoHS & Green	NIPDAU   NIPDAUAG	Level-1-260C-UNLIM	-40 to 125	(R2F, R2R)	Samples
LMV331IDCKRE4	ACTIVE	SC70	DCK	5	3000	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 125	(R2F, R2R)	Samples
LMV331IDCKRG4	ACTIVE	SC70	DCK	5	3000	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 125	(R2F, R2R)	Samples
LMV331IDCKT	ACTIVE	SC70	DCK	5	250	RoHS & Green	NIPDAU   NIPDAUAG	Level-1-260C-UNLIM	-40 to 125	(R2F, R2R)	Samples
LMV331IDCKTE4	ACTIVE	SC70	DCK	5	250	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 125	(R2F, R2R)	Samples
LMV331IDCKTG4	ACTIVE	SC70	DCK	5	250	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 125	(R2F, R2R)	Samples
LMV339ID	ACTIVE	SOIC	D	14	50	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LMV339I	Samples
LMV339IDR	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LMV339I	Samples
LMV339IPW	ACTIVE	TSSOP	PW	14	90	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	MV339I	Samples
LMV339IPWR	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	MV339I	Samples
LMV339IPWRG4	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	MV339I	Samples
LMV339IRUCR	ACTIVE	QFN	RUC	14	3000	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 125	(RT, RTR)	Samples
LMV393ID	ACTIVE	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	MV393I	Samples
LMV393IDDUR	ACTIVE	VSSOP	DDU	8	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	RABR	Samples
LMV393IDGKR	ACTIVE	VSSOP	DGK	8	2500	RoHS & Green	NIPDAU   NIPDAUAG	Level-1-260C-UNLIM	-40 to 125	(R9B, R9Q, R9R)	Samples



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Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
	(-)				,	(-)	(6)	(-)		(32)	
LMV393IDGKRG4	ACTIVE	VSSOP	DGK	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	(R9B, R9Q, R9R)	Samples
LMV393IDR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 125	MV393I	Samples
LMV393IDRG4	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	MV393I	Samples
LMV393IPW	ACTIVE	TSSOP	PW	8	150	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	MV393I	Samples
LMV393IPWG4	ACTIVE	TSSOP	PW	8	150	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	MV393I	Samples
LMV393IPWR	ACTIVE	TSSOP	PW	8	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	MV393I	Samples
LMV393IPWRG4	ACTIVE	TSSOP	PW	8	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	MV393I	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

# **PACKAGE OPTION ADDENDUM**

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**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF LMV331, LMV393:

Automotive: LMV331-Q1, LMV393-Q1

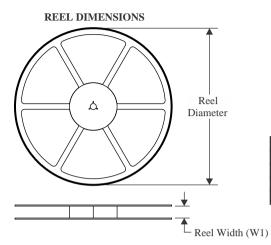
NOTE: Qualified Version Definitions:

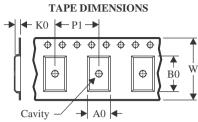
Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects



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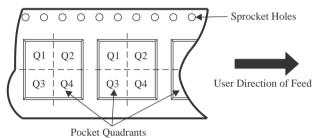
## TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

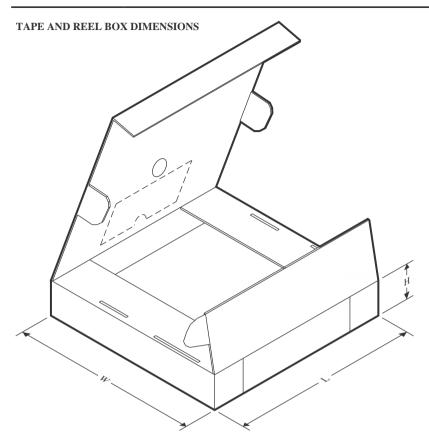


#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LMV331IDBVR	SOT-23	DBV	5	3000	178.0	9.0	3.23	3.17	1.37	4.0	8.0	Q3
LMV331IDBVT	SOT-23	DBV	5	250	178.0	9.0	3.23	3.17	1.37	4.0	8.0	Q3
LMV331IDCKR	SC70	DCK	5	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
LMV331IDCKT	SC70	DCK	5	250	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
LMV339IDR	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
LMV339IPWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
LMV339IRUCR	QFN	RUC	14	3000	180.0	8.4	2.3	2.3	0.55	4.0	8.0	Q2
LMV393IDDUR	VSSOP	DDU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
LMV393IDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
LMV393IDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.3	1.3	8.0	12.0	Q1
LMV393IDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
LMV393IDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
LMV393IDR	SOIC	D	8	2500	330.0	12.8	6.4	5.2	2.1	8.0	12.0	Q1
LMV393IDRG4	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
LMV393IPWR	TSSOP	PW	8	2000	330.0	12.4	7.0	3.6	1.6	8.0	12.0	Q1
LMV393IPWR	TSSOP	PW	8	2000	330.0	12.4	7.0	3.6	1.6	8.0	12.0	Q1



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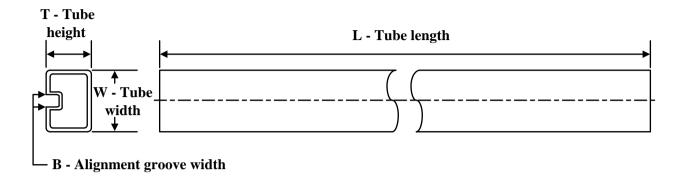
\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
LMV331IDBVR	SOT-23	DBV	5	3000	180.0	180.0	18.0
LMV331IDBVT	SOT-23	DBV	5	250	180.0	180.0	18.0
LMV331IDCKR	SC70	DCK	5	3000	180.0	180.0	18.0
LMV331IDCKT	SC70	DCK	5	250	180.0	180.0	18.0
LMV339IDR	SOIC	D	14	2500	356.0	356.0	35.0
LMV339IPWR	TSSOP	PW	14	2000	356.0	356.0	35.0
LMV339IRUCR	QFN	RUC	14	3000	202.0	201.0	28.0
LMV393IDDUR	VSSOP	DDU	8	3000	202.0	201.0	28.0
LMV393IDGKR	VSSOP	DGK	8	2500	358.0	335.0	35.0
LMV393IDGKR	VSSOP	DGK	8	2500	370.0	355.0	55.0
LMV393IDGKR	VSSOP	DGK	8	2500	364.0	364.0	27.0
LMV393IDR	SOIC	D	8	2500	340.5	336.1	25.0
LMV393IDR	SOIC	D	8	2500	364.0	364.0	27.0
LMV393IDRG4	SOIC	D	8	2500	340.5	336.1	25.0
LMV393IPWR	TSSOP	PW	8	2000	356.0	356.0	35.0
LMV393IPWR	TSSOP	PW	8	2000	356.0	356.0	35.0

# **PACKAGE MATERIALS INFORMATION**

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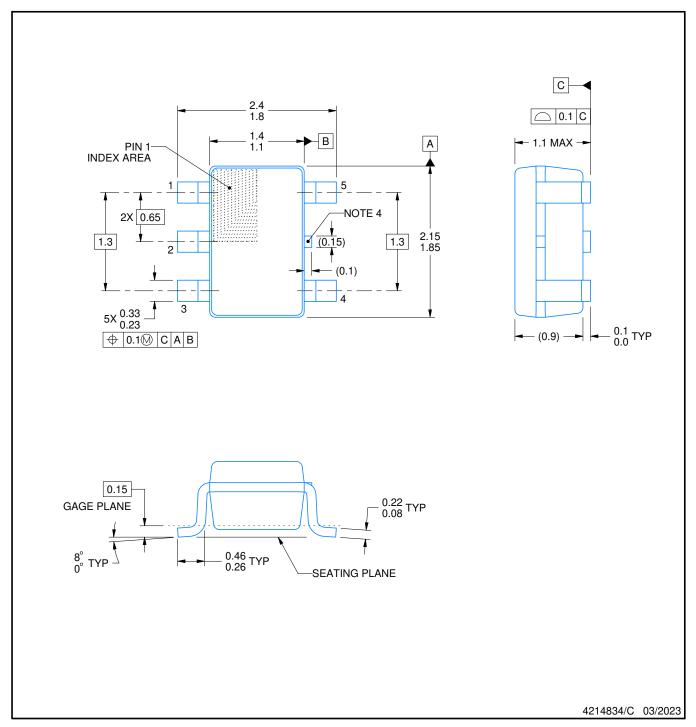
## **TUBE**



\*All dimensions are nominal

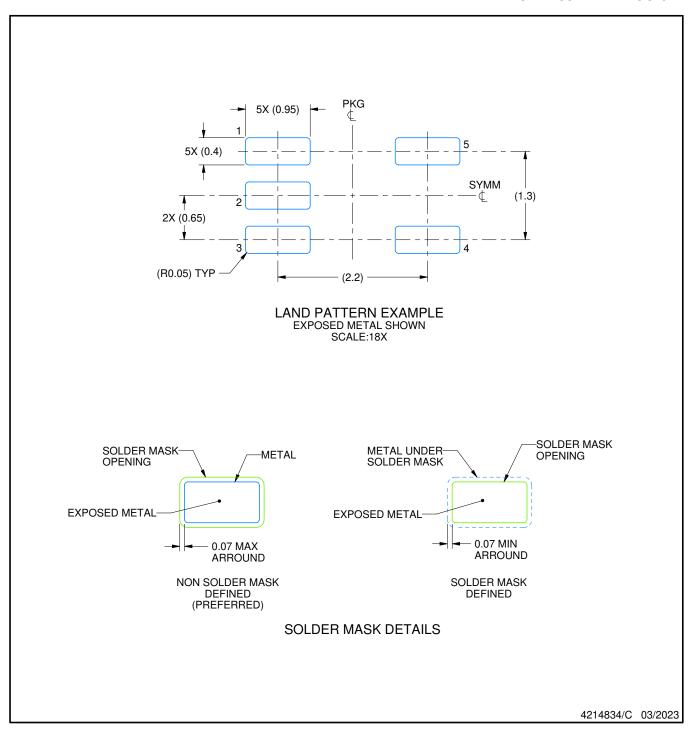
7 III dii rioriororio di o rioriii di								
Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
LMV339ID	D	SOIC	14	50	506.6	8	3940	4.32
LMV339IPW	PW	TSSOP	14	90	530	10.2	3600	3.5
LMV393ID	D	SOIC	8	75	507	8	3940	4.32
LMV393IPW	PW	TSSOP	8	150	530	10.2	3600	3.5
LMV393IPWG4	PW	TSSOP	8	150	530	10.2	3600	3.5





- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
   This drawing is subject to change without notice.
   Reference JEDEC MO-203.
   Support pin may differ or may not be present.

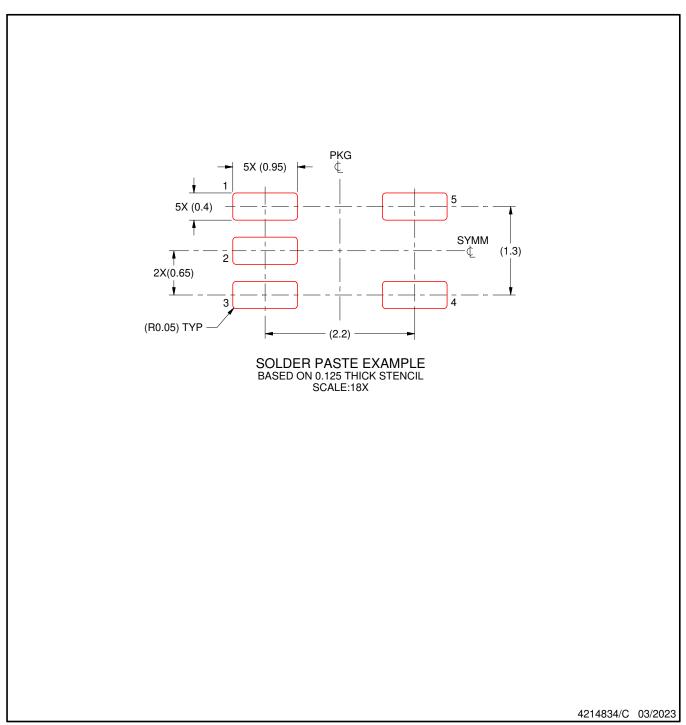




NOTES: (continued)

4. Publication IPC-7351 may have alternate designs.5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





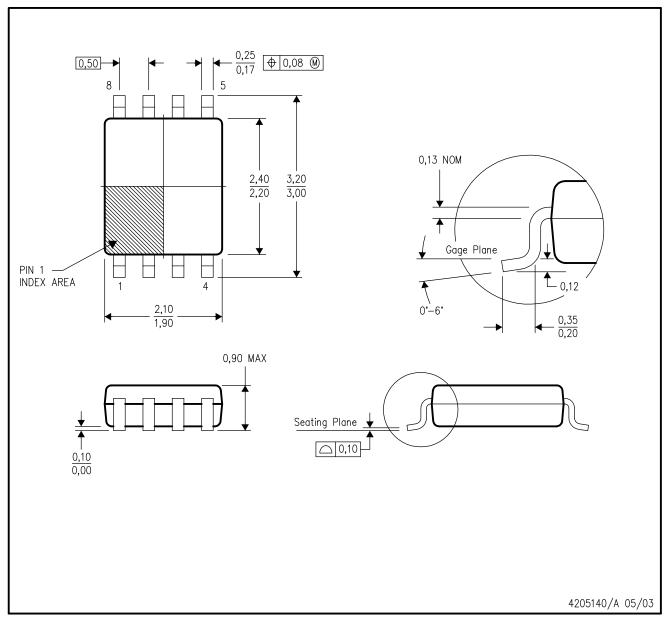
NOTES: (continued)

- 6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 7. Board assembly site may have different recommendations for stencil design.



# DDU (R-PDSO-G8)

# PLASTIC SMALL-OUTLINE PACKAGE

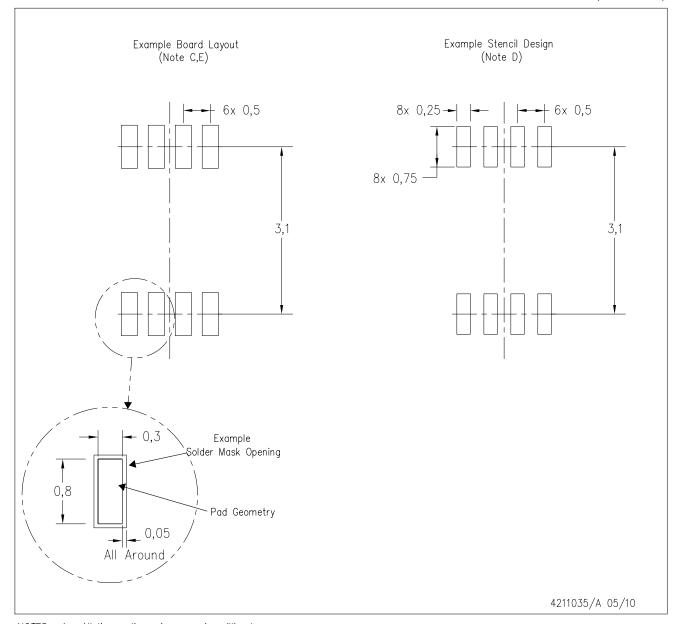


- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion.
- D. Falls within JEDEC MO-187 variation CA.



DDU (S-PDSO-G8)

# PLASTIC SMALL OUTLINE PACKAGE (DIE UP)

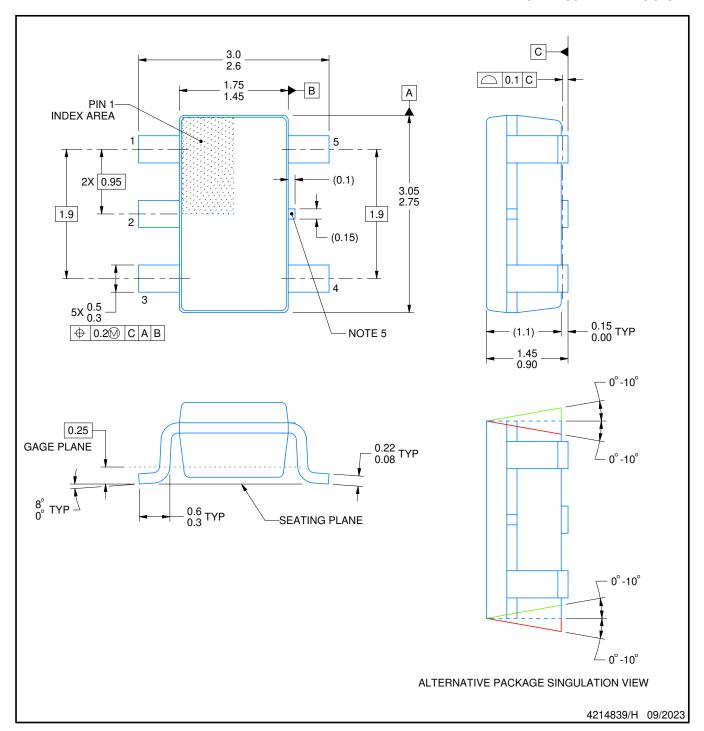


NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



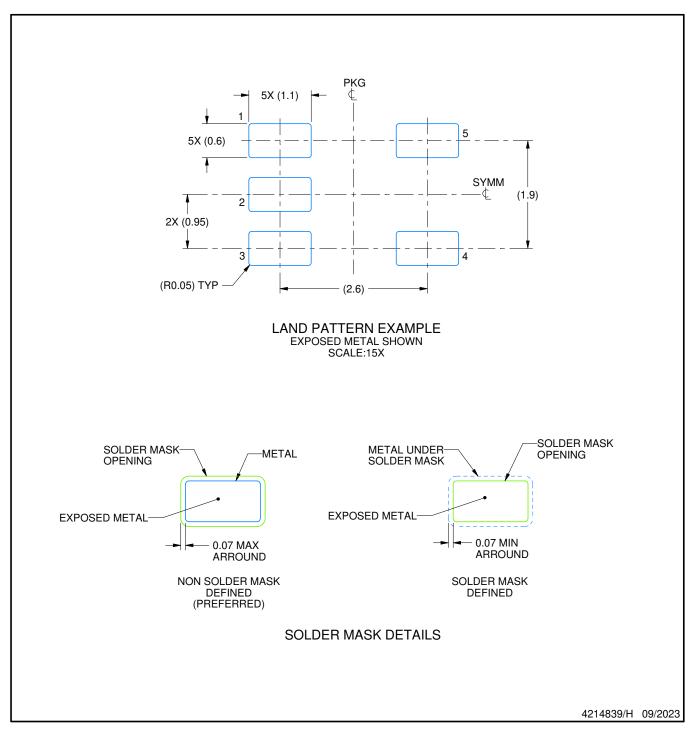




- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
  2. This drawing is subject to change without notice.
  3. Reference JEDEC MO-178.

- 4. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25 mm per side.
- 5. Support pin may differ or may not be present.

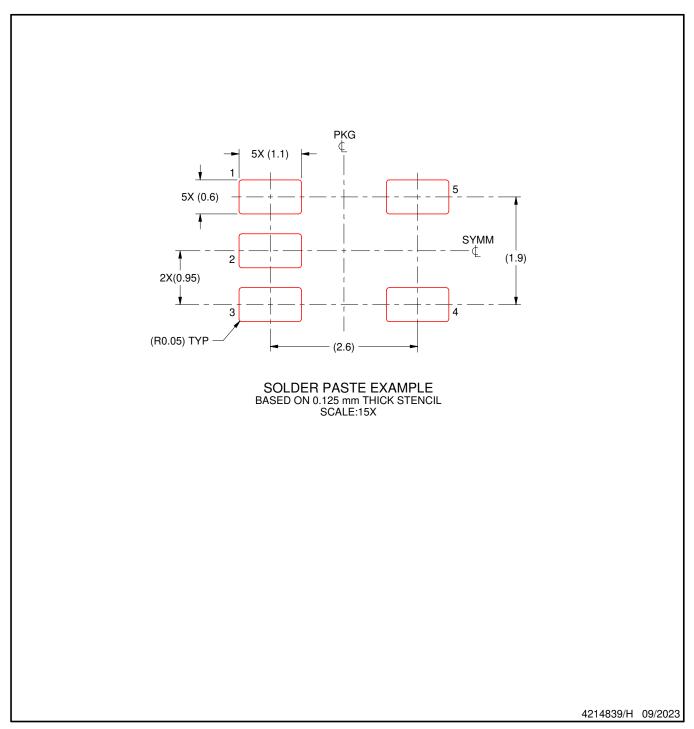




NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



# D (R-PDSO-G14)

## PLASTIC SMALL OUTLINE

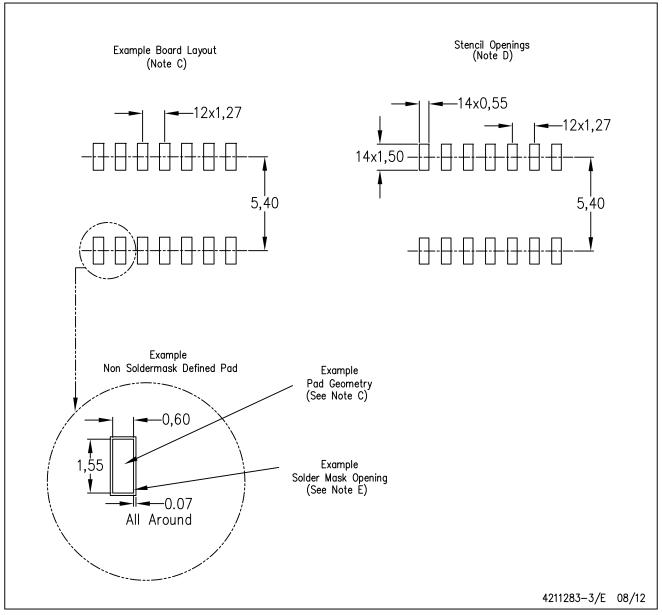


- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AB.



# D (R-PDSO-G14)

# PLASTIC SMALL OUTLINE

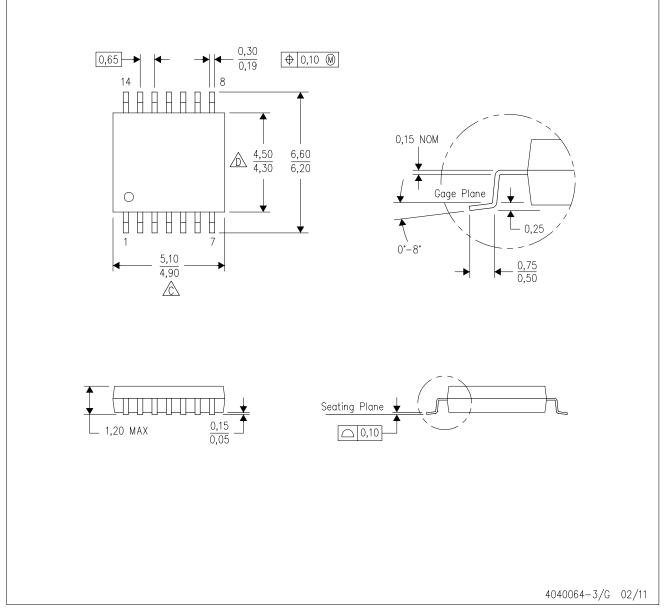


- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



PW (R-PDSO-G14)

## PLASTIC SMALL OUTLINE

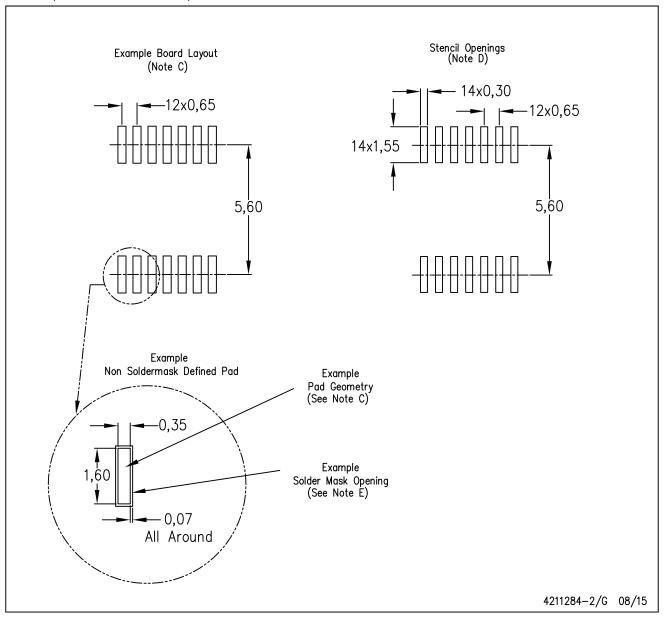


- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



# PW (R-PDSO-G14)

# PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



## **PACKAGE OUTLINE**

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



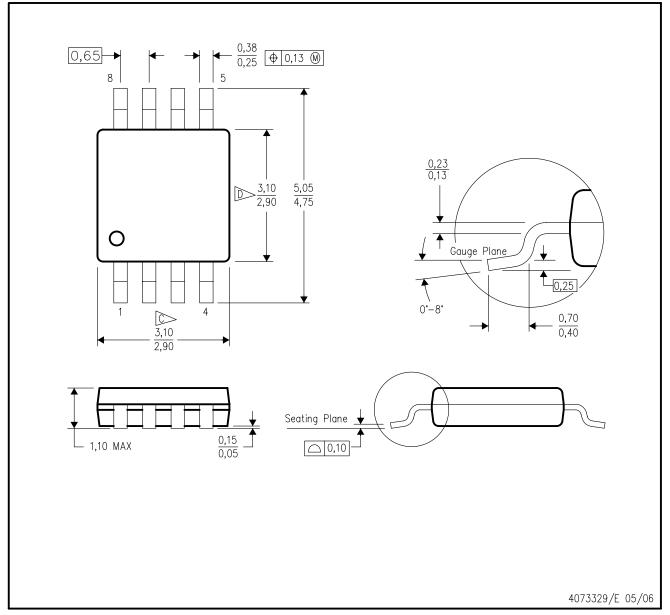
NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



# DGK (S-PDSO-G8)

# PLASTIC SMALL-OUTLINE PACKAGE

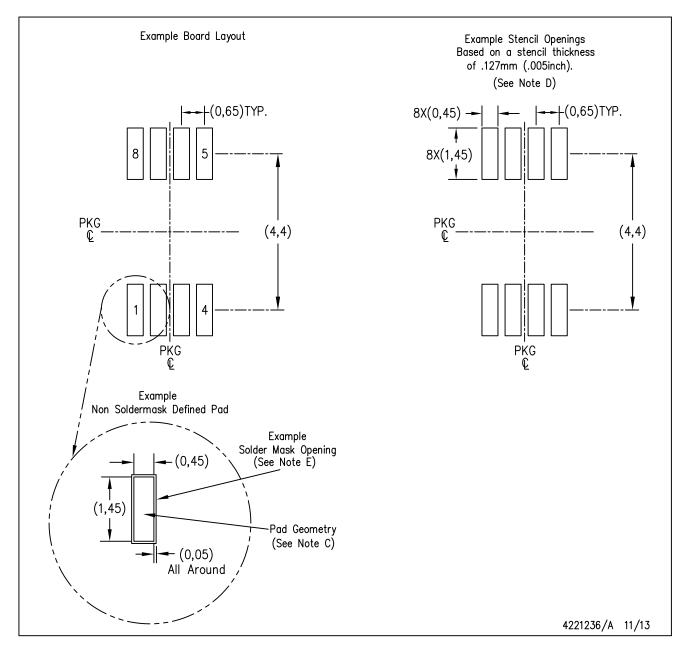


- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per end.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- E. Falls within JEDEC MO-187 variation AA, except interlead flash.



# DGK (S-PDSO-G8)

## PLASTIC SMALL OUTLINE PACKAGE

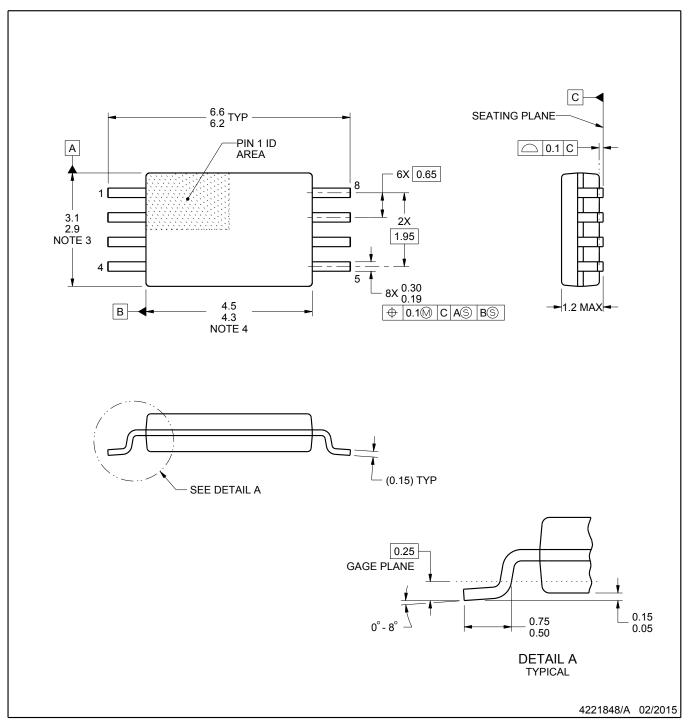


- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.





SMALL OUTLINE PACKAGE



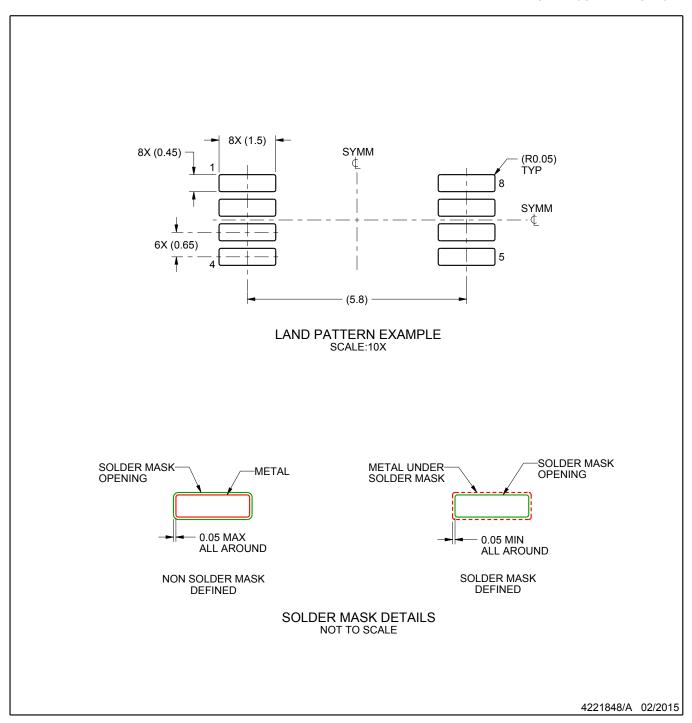
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153, variation AA.



SMALL OUTLINE PACKAGE



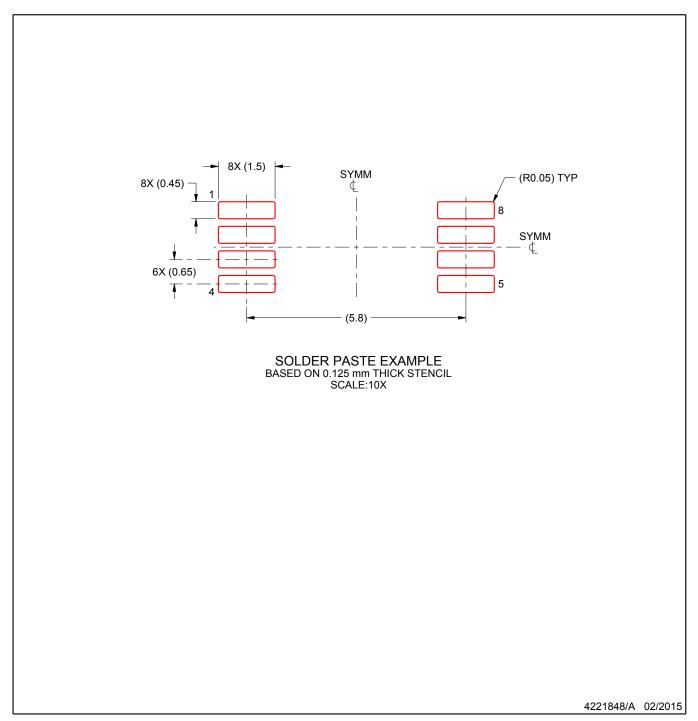
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE

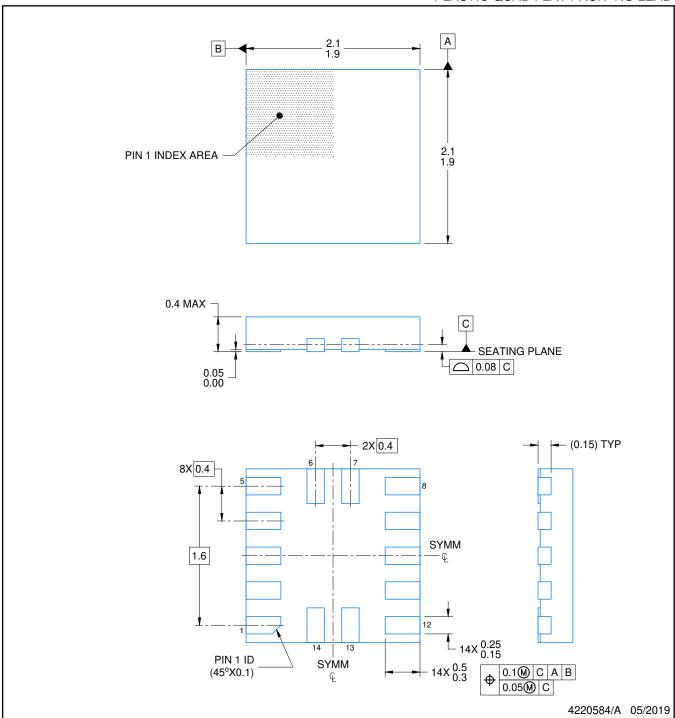


NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



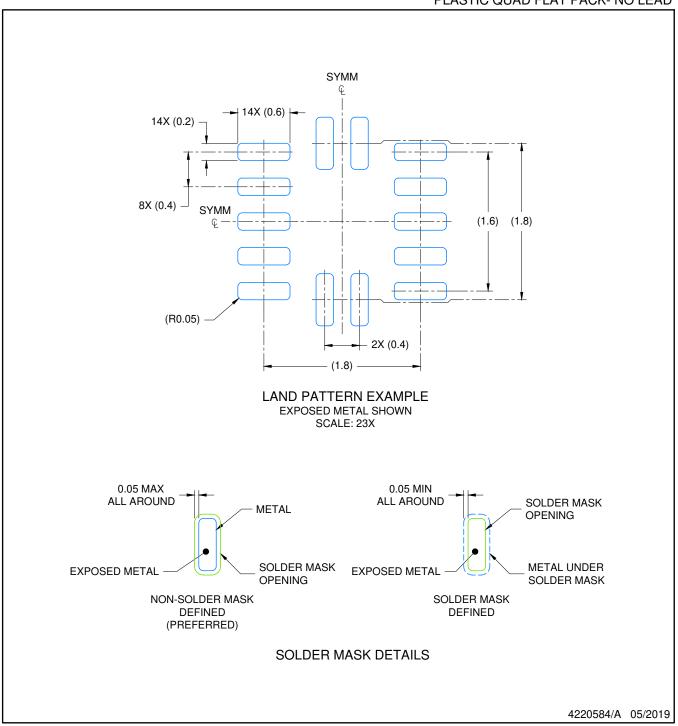
PLASTIC QUAD FLAT PACK- NO LEAD



- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
  This drawing is subject to change without notice.



PLASTIC QUAD FLAT PACK- NO LEAD

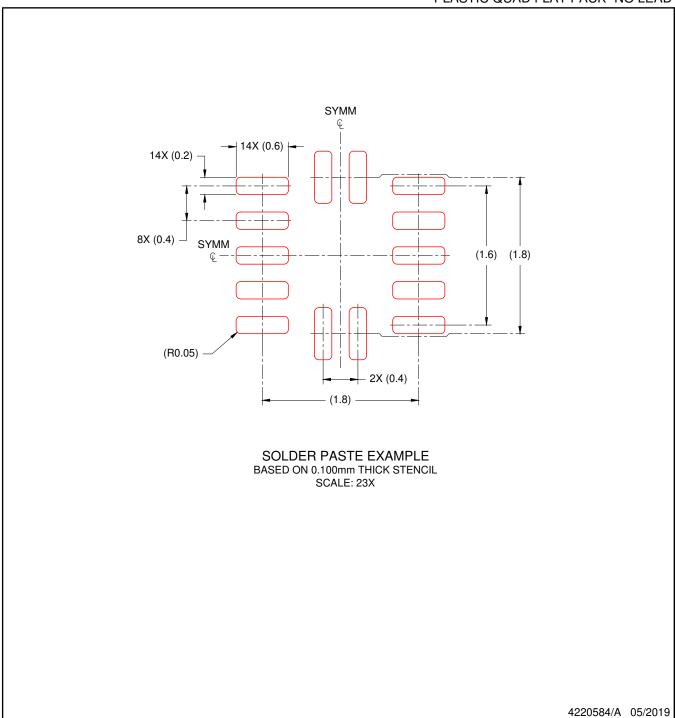


NOTES: (continued)

3. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).



PLASTIC QUAD FLAT PACK- NO LEAD



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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